

MTB11N03Q8-VB Datasheet N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)			
30	0.009 at V _{GS} = 10 V	13	C EnC			
- 50	0.011 at V _{GS} = 4.5 V	12.5	6.5nC			

SO-8

Top View

8 D

D

6 D

5 D

S

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S

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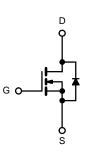
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FEATURES

- Halogen-free
- Trench Power MOSFET
- Optimized for High-Side Synchronous Rectifier Operation
- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

Notebook CPU Core
 High-Side Switch



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS $T_A = 25 \text{ °C}$, unless otherwise noted						
Parameter	Symbol	Limit	Unit			
Drain-Source Voltage		V _{DS}	30	V		
Gate-Source Voltage		V _{GS}	± 20	V		
Continuous Drain Current (T _J = 150 °C) $ \frac{T_{C}}{T_{A}} $ T _A $ T_{A}$		I _D	13 12 12 ^{b, c} 10.5 ^{b, c}	- A		
Pulsed Drain Current	T _C = 25 °C	IDM	45 3.8	_		
Continuous Source-Drain Diode Current	$T_{A} = 25 \text{ °C}$	۱ _S	2.1 ^{b, c}			
Single Pulse Avalanche Current	1 0.1 ml l	I _{AS}	22			
Avalanche Energy L = 0.1 mH		E _{AS}	24	mJ		
Maximum Power Dissipation	$T_{C} = 25 °C$ $T_{C} = 70 °C$ $T_{A} = 25 °C$ $T_{A} = 70 °C$	P _D	4.0 2.6 2.4 ^{b, c} 1.5 ^{b, c}	w		
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 150	°C			

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	38	50	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	22	28	0/11	

Notes:

a. Base on T_C = 25 °C.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s. d. Maximum under Steady State conditions is 85 °C/W.



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					www.VI	Bsemi.c	
SPECIFICATIONS T _J = 25 °C	, unless oth	erwise noted					
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		28			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 230 \mu A$		- 6		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.0		3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zana Osta Malta na Daria Osmanl		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1		
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 \text{ °C}$			10	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	45			А	
		V _{GS} = 10 V, I _D = 11 A		0.009		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V_{GS} = 4.5 V, I _D = 10 A		0.011			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 11 A		52		S	

Dynamic ^b							
Input Capacitance	C _{iss}			1750			
Output Capacitance	C _{oss}	V_{DS} = 15 V, V_{GS} = 0 V, f = 1 MHz		195		pF	
Reverse Transfer Capacitance	C _{rss}			73			
Total Gate Charge	Qg	$V_{DS} = 15 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 11 \text{ A}$		15	23		
Total Gate Gharge	۹g			6.8	10.2	nC	
Gate-Source Charge	Q_gs	V_{DS} = 15 V, V_{GS} = 5 V, I_D = 11 A		2.5			
Gate-Drain Charge	Q _{gd}			2.3			
Gate Resistance	Rg	f = 1 MHz	0.36	1.8	3.6	Ω	
Turn-On Delay Time	t _{d(on)}			16	24		
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.4 Ω		12	18		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ 9 A, V_{GEN} = 4.5 V, R_g = 1 Ω		16	24		
Fall Time	t _f			10	20		
Turn-On Delay Time	t _{d(on)}			8	16	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.4 Ω		10	20	1	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ 9 A, V_{GEN} = 10 V, R_g = 1 Ω		16	24		
Fall Time	t _f			8	15		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			45	A	
Pulse Diode Forward Current ^a	I _{SM}				50		
Body Diode Voltage	V _{SD}	I _S = 9 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			15	30	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 9 A, dl/dt = 100 A/µs, T _J = 25 °C		6	12	nC	
Reverse Recovery Fall Time	t _a	$F = 3 A, avat = 100 Av\mu s, 1 = 25 C$		8			
Reverse Recovery Rise Time	t _b	1		7		ns	

Notes:

a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



T_C = - 55 °C

 $T_C = 25 °C$

С

18

 $V_{GS} = 10 V$

50

75

V_{GS} = 4.5 V

100

125

150

24

30

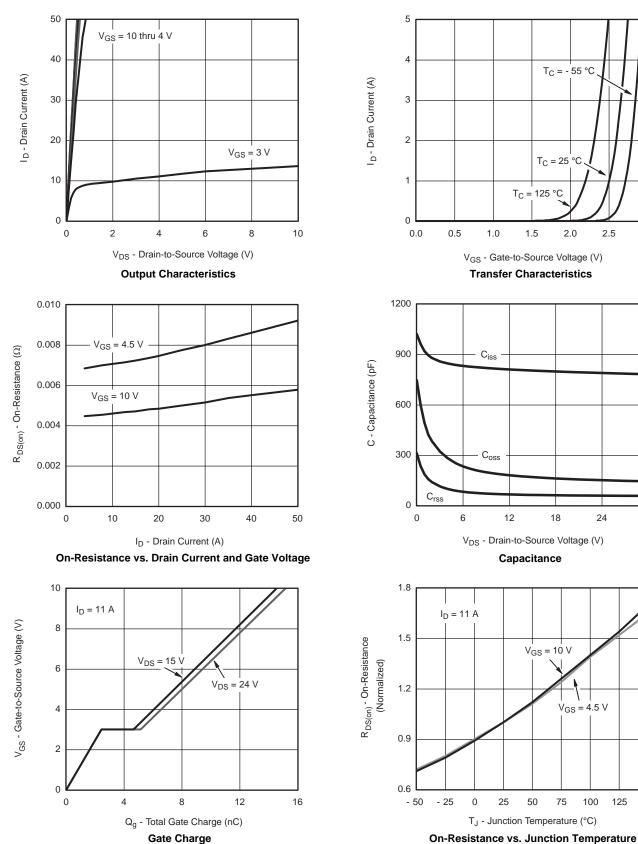
2.0

2.5

3.0

1.5

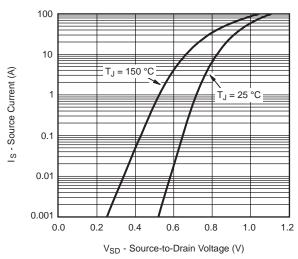
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



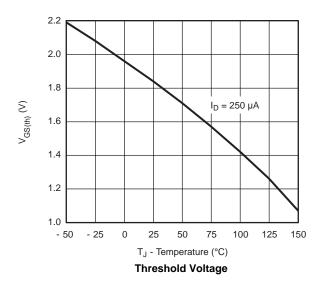


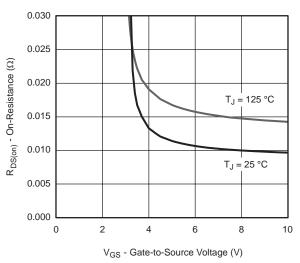


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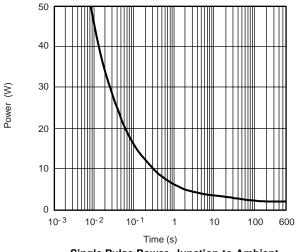




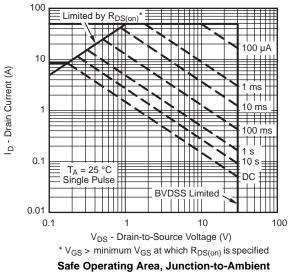




On-Resistance vs. Gate-to-Source Voltage

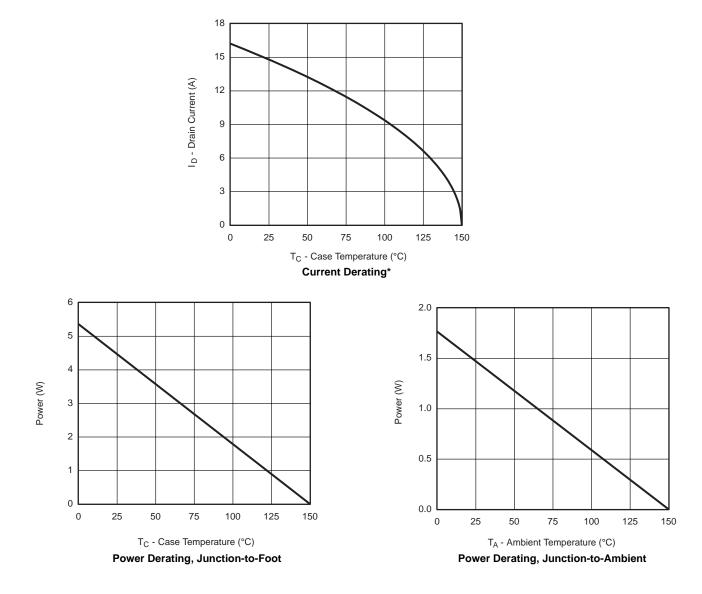






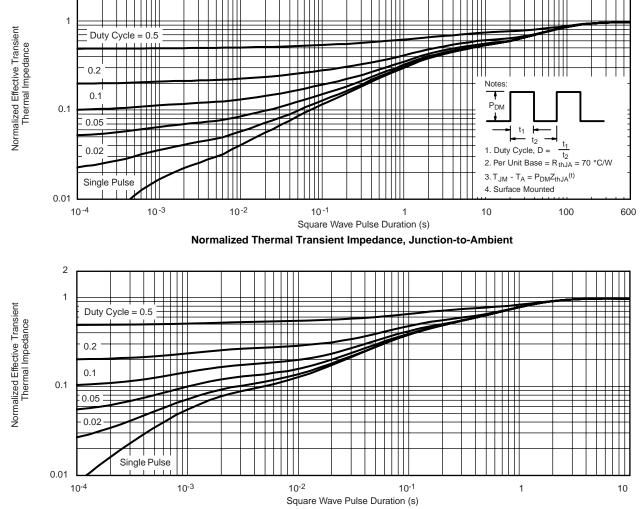


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Normalized Thermal Transient Impedance, Junction-to-Foot

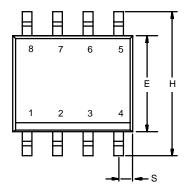
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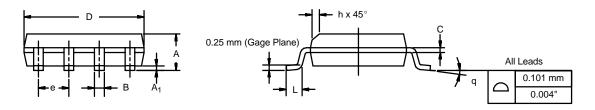
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SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012

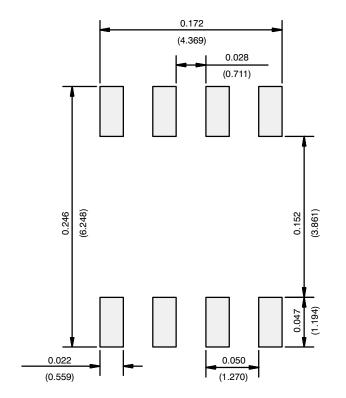




	MILLIMETERS		INC	HES		
DIM	Min	Max	Min	Max		
A	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498						



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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